

Supporting Information

In Situ Formation of ZnO in Graphene: a Facile Way to Produce a Smooth and Highly Conductive Electron Transport Layer for Polymer Solar Cells

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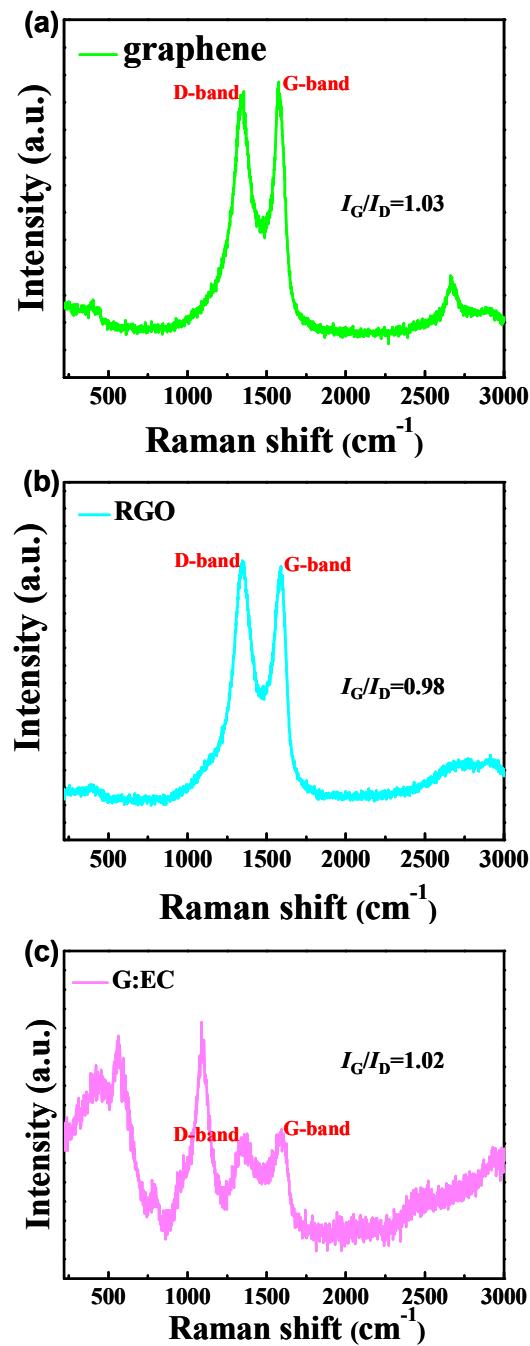


Figure S1. Raman spectra of (a) graphene, (b) reduced graphene oxide (RGO), (c) graphene:ethyl cellulose (G:EC).

Two chiefly characteristic peak of graphene materials were exhibited in **Figure S1**, one of which is the G peak. The G peak appears at about 1584 cm^{-1} , which was attributed to the phonon vibration with E_{2g} symmetry and was the characteristic peak of the sp^2 hybrid carbon structure. The other was D peak at approximately 1350 cm^{-1}

result from the A_{1g} mode of representative defects concerned with structure defect or the sp^3 hybrid carbon atoms. The intensity ratio of the G and D bands (I_G/I_D) decreased from 1.03 for graphene to 0.98 for reduced graphene oxide (RGO), which could be attributed to an enhancive number of defects during the thermal reduction process. Moreover, I_G/I_D was almost equivalent for graphene and G:EC, which Hxposed EC could well disperse graphene. As for the large differences of Raman spectra of graphene and G:EC, the reason could impute the presence of EC.

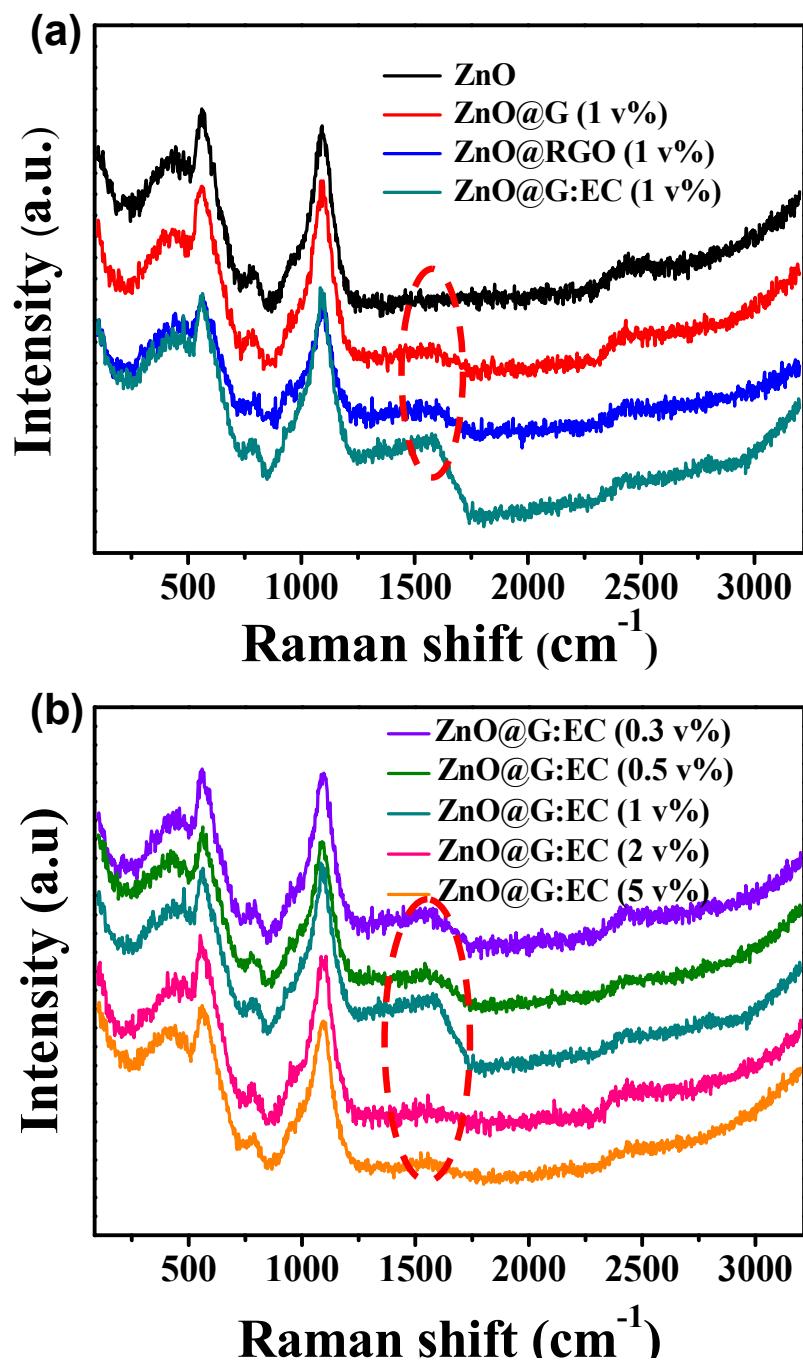


Figure S2. (a) Raman spectra of zinc oxide (ZnO), ZnO@graphene (ZnO@G) (1 v%), ZnO@reduced graphene oxide (ZnO@RGO) (1 v%), ZnO@graphene:ethyl cellulose (ZnO@G:EC) (1 v%) and (b) the Raman spectra of ZnO@G:EC with various volume fraction.

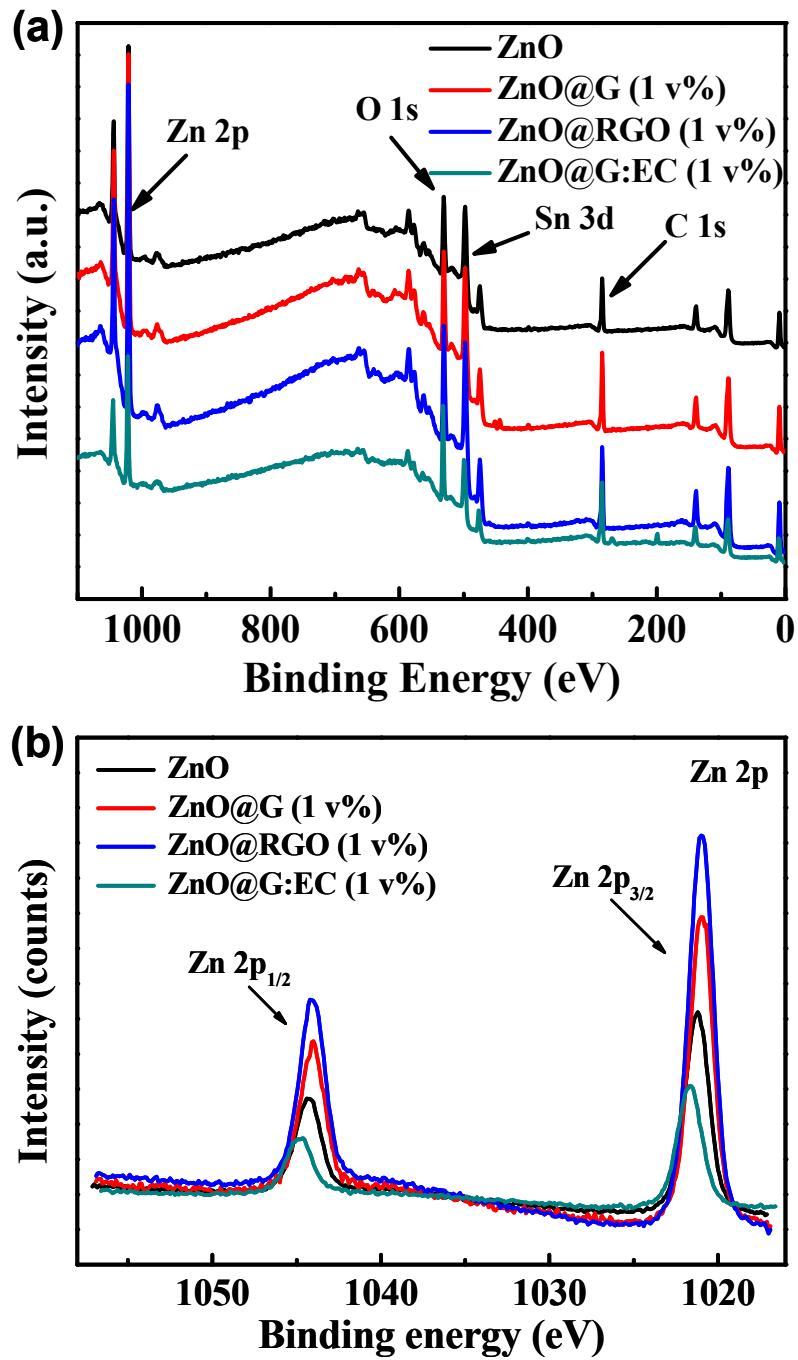


Figure S3. (a) Survey X-ray photoelectron spectra (XPS) of ZnO, ZnO@G (1 v%), ZnO@RGO (1 v%), ZnO@G:EC (1 v%) and (b) high-resolution XPS of Zn 2p for ZnO, ZnO@G (1 v%), ZnO@RGO (1 v%), ZnO@G:EC (1 v%).

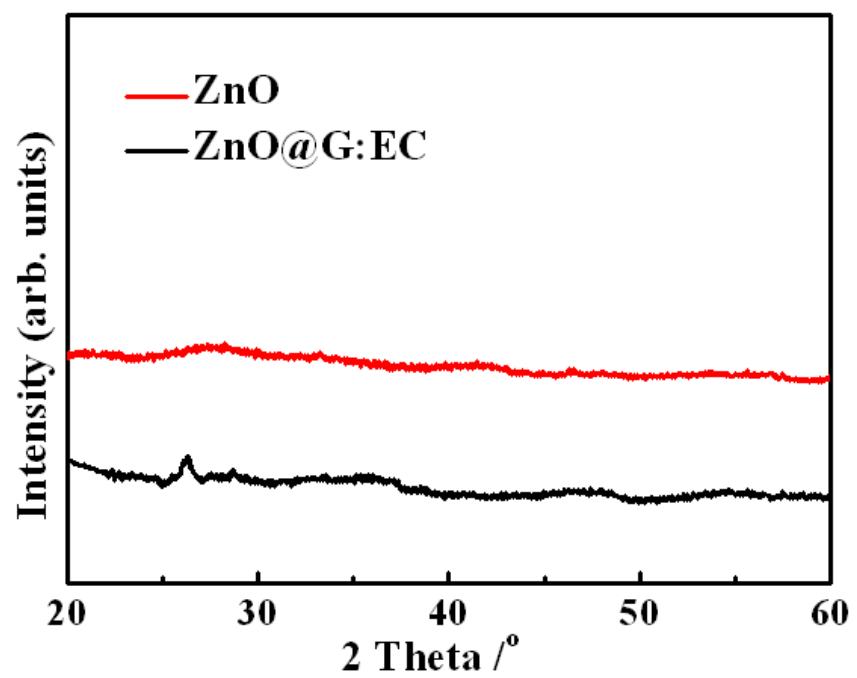


Figure S4. X-ray diffraction (XRD) patterns of ZnO, ZnO@G:EC samples that have been heat treated (150 °C).

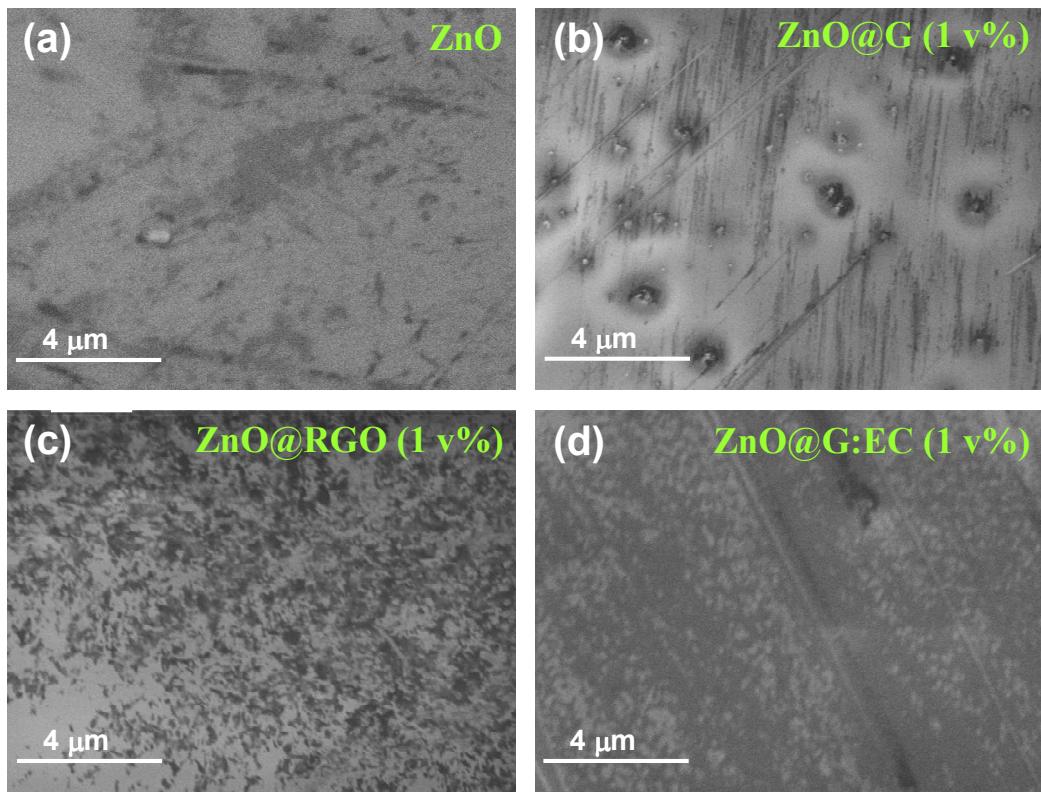


Figure S5. Scanning electron microscopy (SEM) images of (a) ZnO, (b) ZnO@G (1 v%), (c) ZnO@RGO (1 v%) and (d) ZnO@G:EC (1 v%).

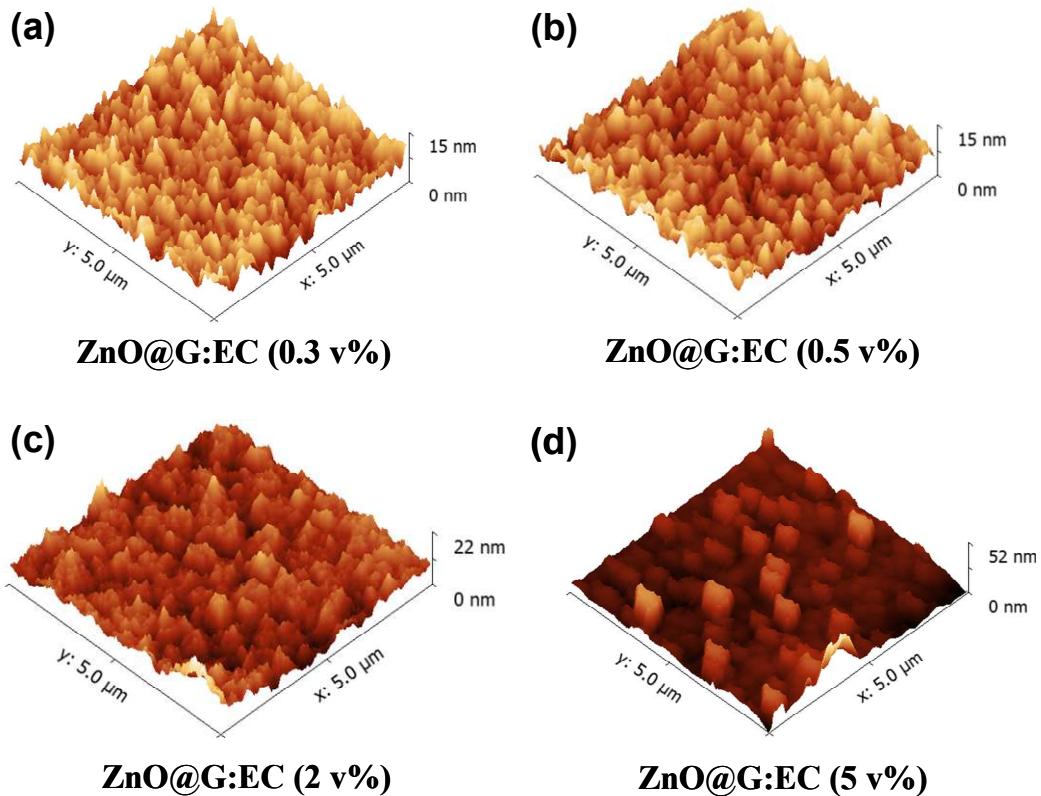


Figure S6. Atomic Force Microscopy (AFM) micrographs of (a) ZnO@G:EC (0.3 v%), (b) ZnO@G:EC (0.5 v%), (c) ZnO@G:EC (2 v%), (d) ZnO@G:EC (5 v%) on top of the ITO.

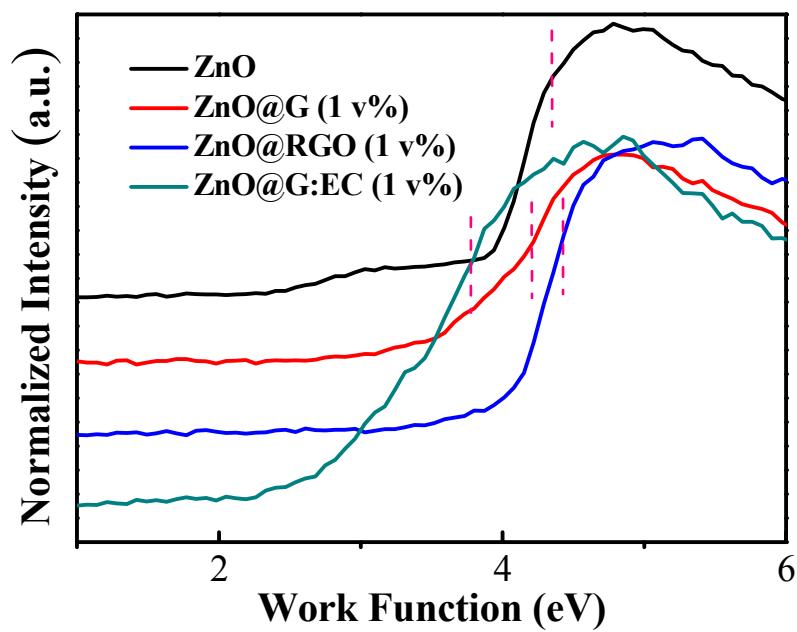


Figure S7. Ultraviolet photoelectron spectroscopy (UPS) spectra of ZnO, ZnO@G (1 v%), ZnO@RGO (1 v%), ZnO@G:EC (1 v%).

Table S1. the work function of ZnO, ZnO@G, ZnO@RGO, ZnO@G:EC.

ETLs	ZnO	ZnO@G (1 v%)	ZnO@RGO (1 v%)	ZnO@G:EC (1 v%)
Work Function (eV)	4.35	4.21	4.43	3.78

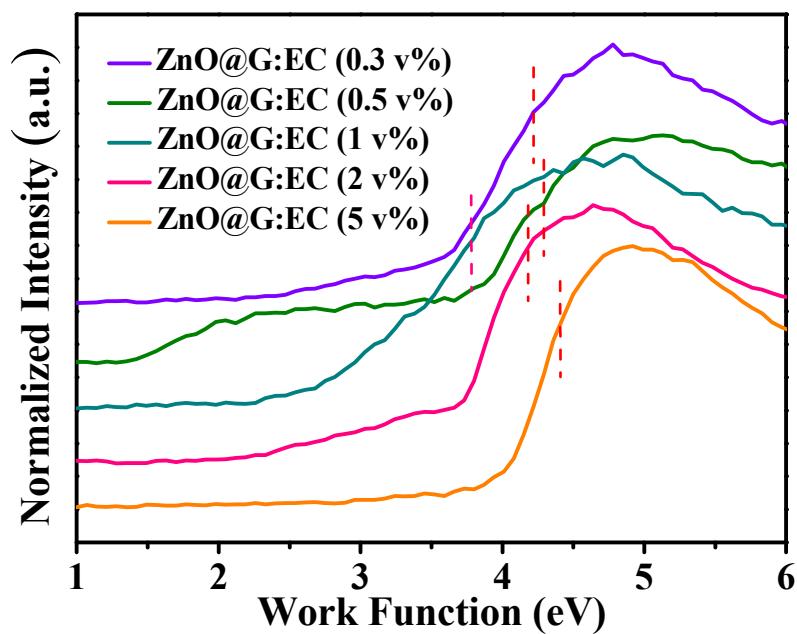


Figure S8: Ultraviolet photoelectron spectroscopy (UPS) spectra of ZnO@G:EC with various volume fraction.

Table S2. the work function of ZnO@G:EC with various volume fraction.

ETLs	ZnO@G:EC (0.3 v%)	ZnO@G:EC (0.5 v%)	ZnO@G:EC (1 v%)	ZnO@G:EC (2 v%)	ZnO@G:EC (5 v%)
Work Function (eV)	4.21	4.28	3.78	4.17	4.40

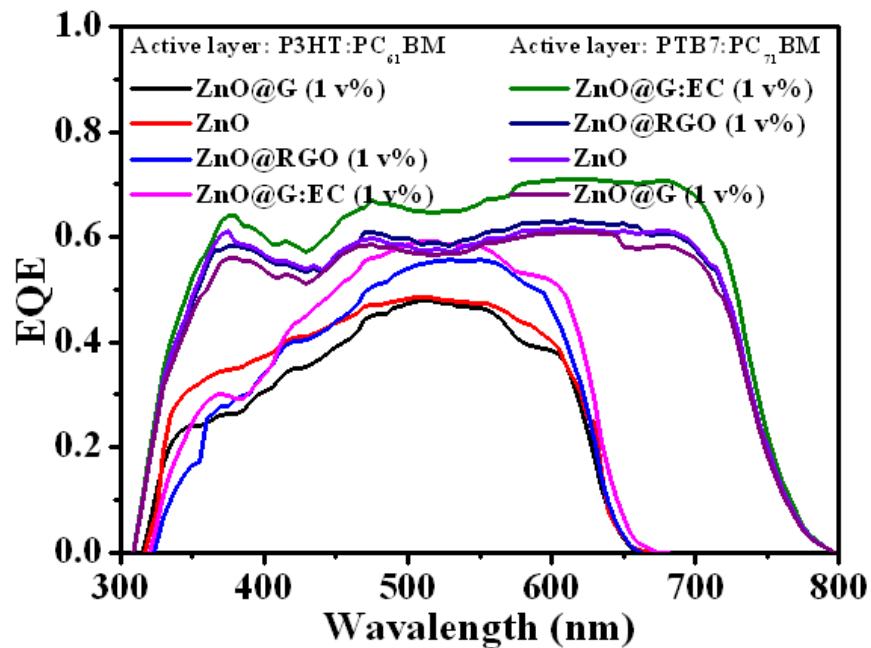


Figure S9: Corresponding external quantum efficiency (EQE) spectra of devices with different electron transfer layers (ZnO, ZnO@G (1 v%), ZnO@RGO (1 v%) and ZnO@G:EC (1 v%)) and active layers (P3HT:PC₆₁BM and PTB7:PC₇₁BM).

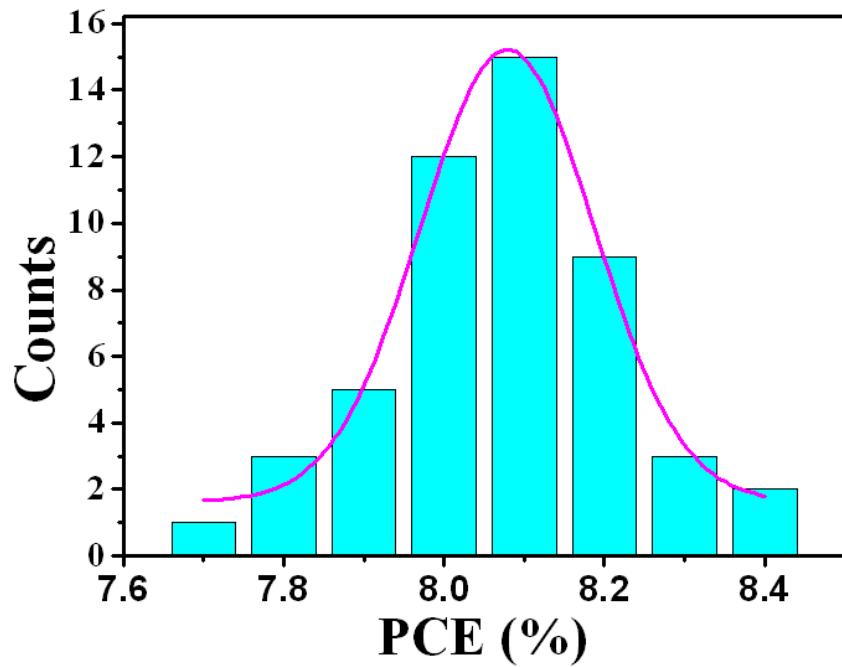


Figure S10: Histogram of power conversion efficiency (PCE) for 50 devices:
ITO/ZnO@G:EC (1 v%) /PTB7:PC₇₁BM/MoO₃/Ag.